

Abstract

The invention relates to a test adapter (1) for operatively connecting a chip to be tested to a test device. The test adapter has a three-dimensional construction with a baseplate (8) and a cover plate (2). The cover plate (2) has a contact array (3) having contact elements (9) coordinated with the chip to be tested in terms of number and arrangement. Arranged between the baseplate (8) and the cover plate (2) are side faces (4) which are arranged at an angle with respect to the cover plate (2) and have a number of individual connectors (5) that is coordinated with the chip to be tested.

(Figure 1)
